FAIRCHILD SEMICONDUCTOR®

February 2007

FDMC8854
N-Channel Power Trench® MOSFET
30V, 15A, 5.7mΩ

Features

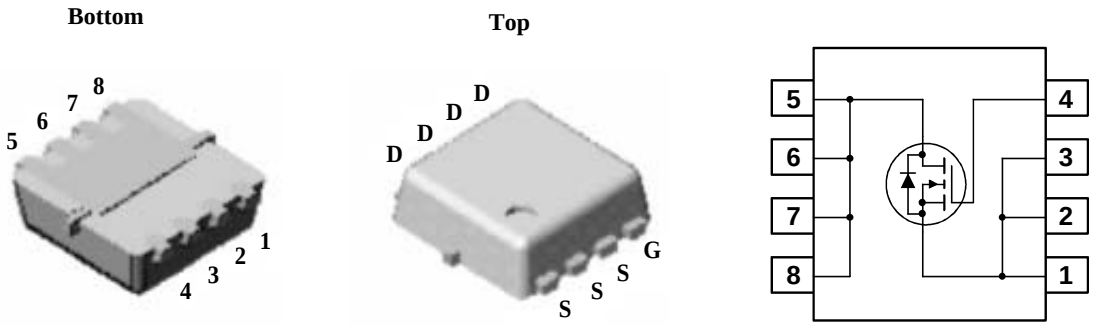
- Max $r_{DS(on)}$ = 5.7mΩ at V_{GS} = 10V, I_D = 15A
- Max $r_{DS(on)}$ = 7.6mΩ at V_{GS} = 4.5V, I_D = 13A
- Low Profile - 1mm max in Power 33
- RoHS Compliant

General Description

This N-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced Power Trench process. It has been optimized for power management applications.

Application

- DC - DC Conversion



Power 33

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage			±20	V
I_D	Drain Current -Continuous (Package limited)	T_C = 25°C		15	A
	-Continuous (Silicon limited)	T_C = 25°C		67	
	-Continuous	T_A = 25°C	(Note 1a)	15	
	-Pulsed			30	
P_D	Power Dissipation	T_C = 25°C		41	W
	Power Dissipation	T_A = 25°C	(Note 1a)	2.0	
T_J, T_{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	60	

Package Marking and Ordering Information

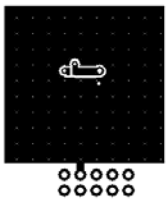
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8854	FDMC8854	Power 33	7"	8mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250μA, V_{GS} = 0V	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		21		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 24V, V_{GS} = 0V			1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20V, V_{GS} = 0V			±100	nA
On Characteristics (Note 2)						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250μA	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		-6		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10V, I_D = 15A		4.4	5.7	mΩ
		V_{GS} = 4.5V, I_D = 13A		5.6	7.6	
		V_{GS} = 10V, I_D = 15A, T_J = 125°C		6.6	9.0	
g_{FS}	Forward Transconductance	V_{DS} = 5V, I_D = 15A		60		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 10V, V_{GS} = 0V, f = 1MHz		2560	3405	pF
C_{oss}	Output Capacitance			515	685	pF
C_{rss}	Reverse Transfer Capacitance			290	435	pF
R_g	Gate Resistance	f = 1MHz		1.3		Ω
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 10V, I_D = 15A V_{GS} = 10V, R_{GEN} = 6Ω		13	23	ns
t_r	Rise Time			5	10	ns
$t_{d(off)}$	Turn-Off Delay Time			31	50	ns
t_f	Fall Time			5	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V_{DD} =10V, I_D = 15A, V_{GS} = 10V		41	57	nC
Q_{gs}	Gate to Source Gate Charge			7		nC
Q_{gd}	Gate to Drain “Miller” Charge			7		nC
Drain-Source Diode Characteristics						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0V, I_S = 15A (Note 2)		0.8	1.3	V
t_{rr}	Reverse Recovery Time	I_F = 15A, di/dt = 100A/μs		33	50	ns
Q_{rr}	Reverse Recovery Charge			28	42	nC

Notes:

1: $R_{\theta JA}$ is determined with the device mounted on a 1in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 60°C/W when mounted on a 1 in^2 pad of 2 oz copper

b. 135°C/W when mounted on a minimum pad of 2 oz copper

2: Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

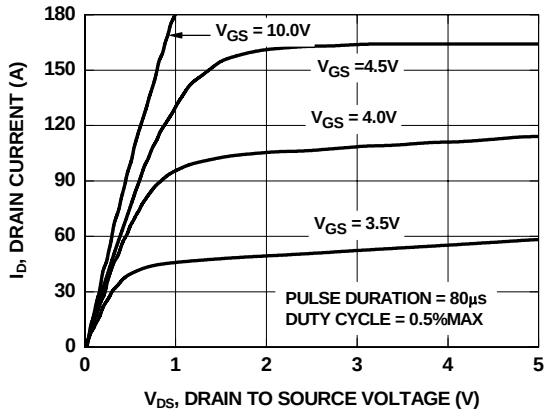


Figure 1. On-Region Characteristics

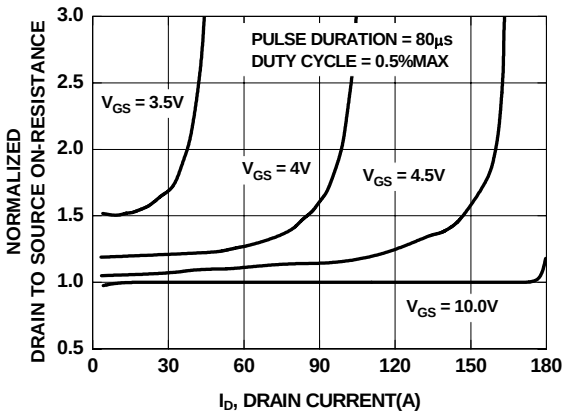


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

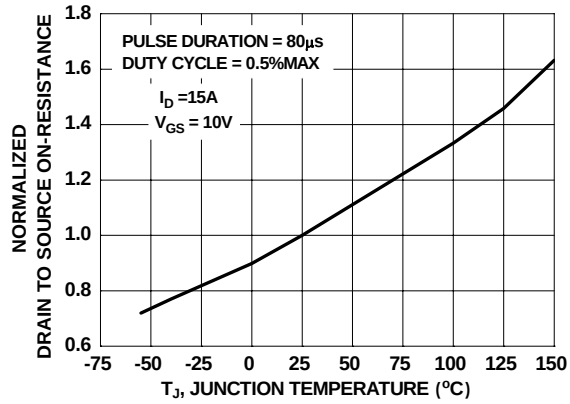


Figure 3. Normalized On-Resistance vs Junction Temperature

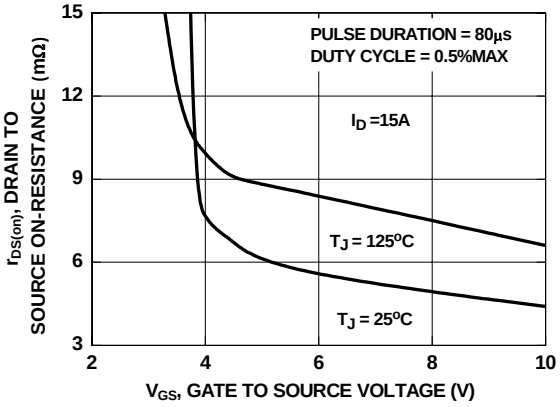


Figure 4. On-Resistance vs Gate to Source Voltage

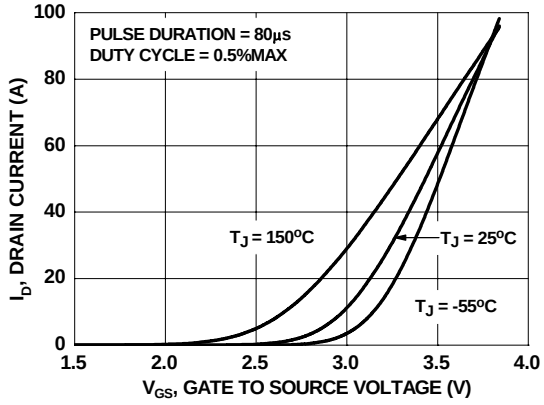


Figure 5. Transfer Characteristics

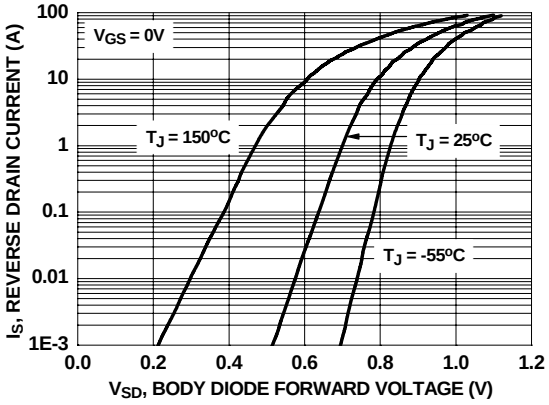


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

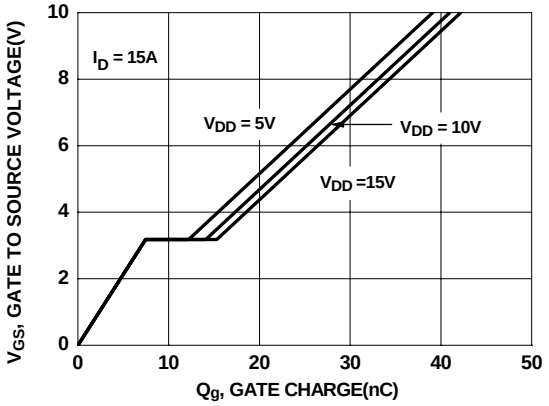


Figure 7. Gate Charge Characteristics

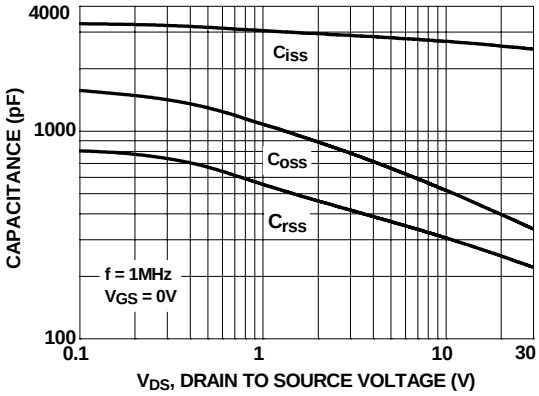


Figure 8. Capacitance vs Drain to Source Voltage

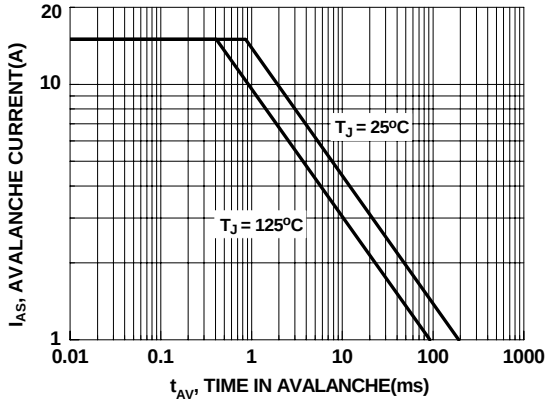


Figure 9. Unclamped Inductive Switching Capability

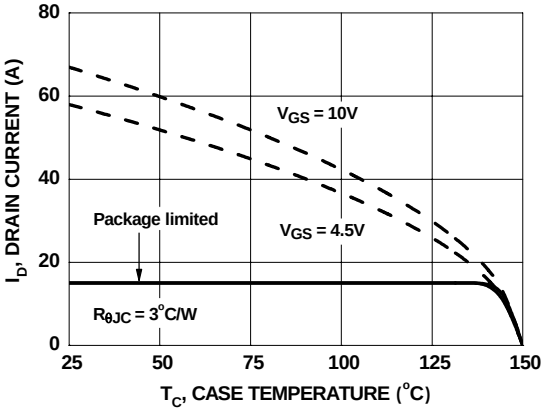


Figure 10. Maximum Continuous Drain Current vs Case Temperature

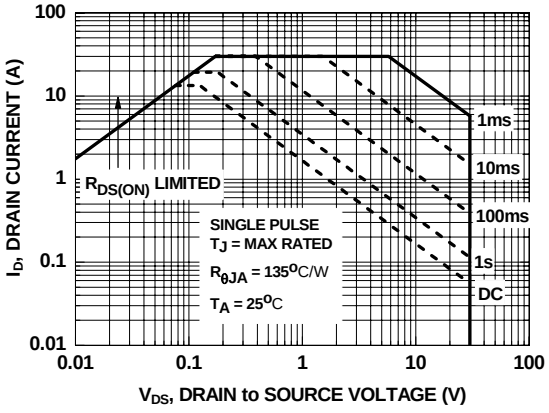


Figure 11. Forward Bias Safe Operating Area

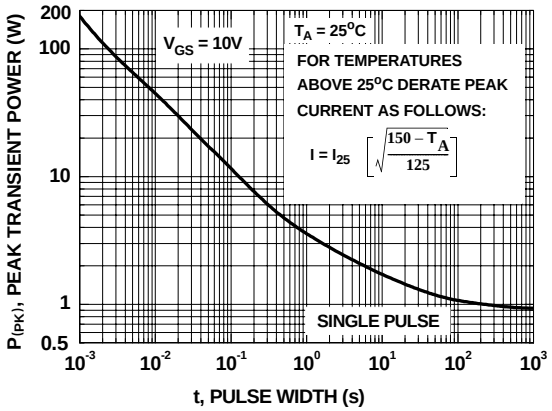


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

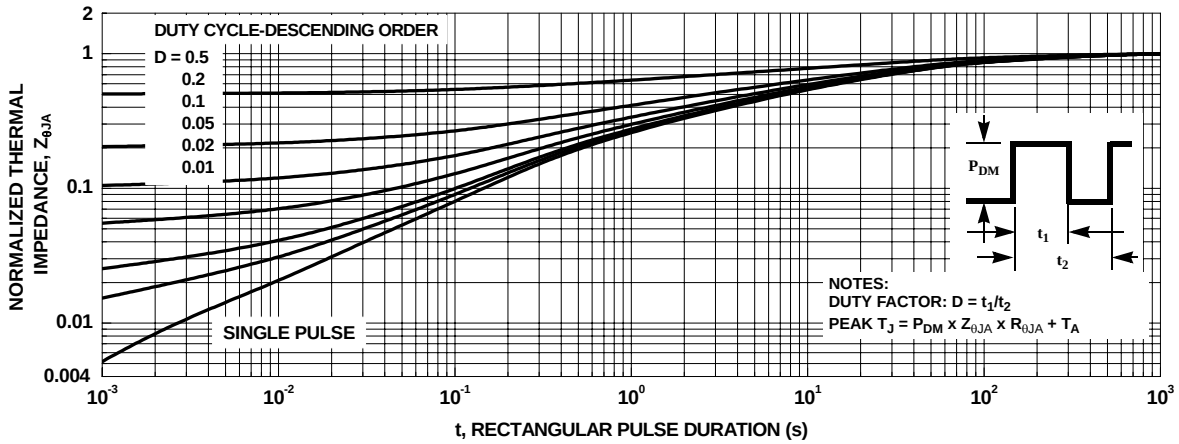
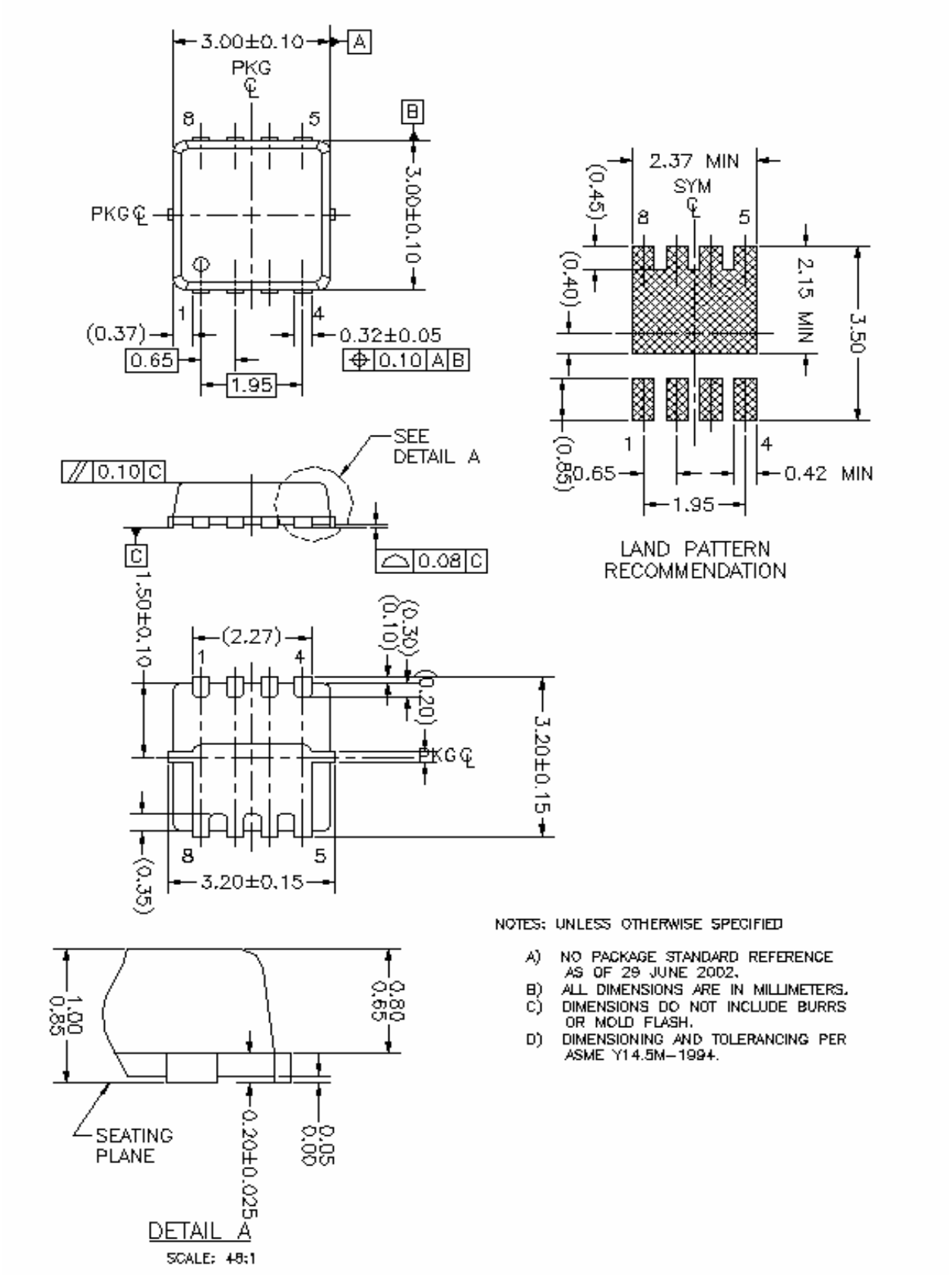


Figure 13. Transient Thermal Response Curve



NOTES: UNLESS OTHERWISE SPECIFIED

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Rev. I22